



## PATENT APPLICATION

Sheet 1 of 2

 <b>FORM PTO-1449</b> <b>LIST OF PATENTS AND PUBLICATIONS FOR</b> <b>APPLICANT'S INFORMATION DISCLOSURE</b> <b>STATEMENT</b>  <b>(Use several sheets if necessary)</b>	<b>ATTY. DOCKET NO.</b> <b>10010958-1</b>	<b>SERIAL NO.</b> <b>10/047,344</b>
	<b>APPLICANT</b> <b>Kang Wu et al</b>	
	<b>FILING DATE</b> <b>01/15/2002</b>	<b>GROUP</b> <b>2184</b>

**REFERENCE DESIGNATION**

## **U.S. PATENT DOCUMENTS**

**RECEIVED**

AUG 06 2003

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## **FOREIGN PATENT DOCUMENTS**

	DOCUMENT NUMBER	DATE	NAME	TRANSLATION	
				YES	NO
20	EP 1132749 A	Sep 12, 2001	Toshinori Hosokawa et al	x	

**OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)**

EA	<p>Coudert, Olivier, "On Solving Covering Problems", 33rd Design Automation Conference, Proceedings 1996 (IEEE Cat.No.96CH35932), Proceedings of 33rd Design Automation Conference, Las Vegas, NV, USA, 3-7 June 1996, 1996, New York, NY, USA, ACM, USA, Page(s) 197-202. XP002246-016 ISBN: 0-89791-779-0</p>
EA	<p>Fallah, Farzan et al, "Solving Covering Problems Using LPR-Based Lower Bounds", IEEE Trans. Very Large Scale Integr. (VLSI) Syst. (USA), IEEE Transactions on Very Large Scale Integration (VLSI) Systems, Feb. 2000, IEEE, USA, vol.8, no.1, pages 9-17, XP002246015 ISSN: 1063-8210</p>
EA	<p>Coudert, Olivier, "Solving Graph Optimization Problems with ZBDDs", European Design and Test Conference, 1997, ED&amp;TC 97, Proceedings Paris, France 17-20 March 1997, Los Alamitos, CA, USA, IEEE Comput. Soc, US, Page(s) 224-228. XP010218503 ISBN: 0-8186-7786-4</p>

**EXAMINER**

Esaw Abraham

**DATE CONSIDERED**

12/01/04

\* Copies of these references are not enclosed pursuant to 37 CFR 1.98(d). (See accompanying IDS)



**PATENT APPLICATION**

Sheet 2 of 2

FORM PTO-1449

**LIST OF PATENTS AND PUBLICATIONS FOR  
APPLICANT'S INFORMATION DISCLOSURE  
STATEMENT**

(Use several sheets if necessary)

**ATTY. DOCKET NO.**

**SERIAL NO.**

10010958-1

KOMA M.

**RANG WU**

01/15/2003

GROUP  
2184

## **REFERENCE DESIGNATION**

## U.S. PATENT DOCUMENTS

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AUG 06 2003

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## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	NAME	TRANSLATION
					YES NO

**OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)**

ED	<p>Brosa, Anna M et al, "On Maximizing the Coverage of Catastrophic and Parametric Faults", European Test Workshop 1999 (CAT. No.PR00390), European Test Workshop 1999, Constance, Germany, 25-28 May 1999, 1999, Los Alamitos, CA, USA, IEEE Comput. Soc, USA, Page(s) 123-128. XP002246017 ISBN: 0-7695-0390-X</p>

**EXAMINER**

Saw Abraham

**DATE CONSIDERED**

12/01/04

\* Copies of these references are not enclosed pursuant to 37 CFR 1.98(d). (See accompanying IDS)